



DOCUMENT CHANGE REQUEST

DCR number	1463	Changes required for: General	Originator: Steve Jeffery
Date: 2021/11/26		Date sent: 2021/09/09	Organisation: ESCC Executive
Status: IMPLEMENTED			

Title:	TRANSISTORS, POWER, MOSFET, N-CHANNEL, RAD-HARD BASED ON TYPE STRH100N6
--------	---

Number:	5205/022	Issue:	8
---------	----------	--------	---

Other documents affected:

5205/023-9, 5205/024-9, 5205/025-7

Page:

As applicable (see each individual Detail Specification)

Paragraph:

"Electrical Measurements for Total Dose Radiation Testing"; Appendix A

Original wording:

Characteristics are specified in the Electrical Measurements for Total Dose Radiation Testing table for "Total Gate Charge", "Gate-to-Source Charge" and "Gate-to-Drain Charge" (Qg, Qgs and Qgd)

Proposed wording:

- Qg, Qgs and Qgd are removed from the Electrical Measurements for Total Dose Radiation Testing table
- The associated Agreed Deviation given in Appendix A is deleted.

Justification:

Note: This DCR has been raised by the ESCC T.W. on behalf of the ESCC Qualified mfr STMicroelectronics.

Alignment of the Electrical Measurements for Total Dose Radiation Testing across a range of specs for similar device types (supported by 2 mfrs: STMicroelectronics & Infineon).

i.e.: The parameters Qg, Qgs and Qgd are not included in the Electrical Measurements for Total Dose Radiation Testing table in the existing published Detail Specs 5205/021, /026, /027, /028, /029, /030, /031, /032 & /033.

Attachments:
N/A
Modifications:
N/A
Approval signature:

Date signed:
2021-11-26